Searcn Notes			

	Application/Control No.	Applicant(s)/Patent unde Reexamination	r
	10/725,521	SHIRIE, NOBUYUKI	
Ī	Examiner	Art Unit	
	Thong Q. Nguyen	2872	

	SEARCHED		
Class	Subclass	Date	Examiner
359	601-614; 811-830; 738-740	5/20/2005	NT
396	29,72	5/20/2005	NT
396	349,535	5/20/2005	NT

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH (INCLUDING SEAF		()
•	DATE	EXMR
East (search attached)	5/19/2005	NT
East (search attahced)	5/20/2005	NT